

FPGA IRRADIATION @ NPTC-MGH (Part 2)

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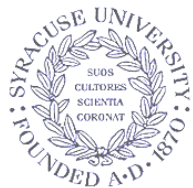
Syracuse University



Outline

- **Progress with firmware**
 - Solved timing/delay issues, ...
- **Progress with hardware**
 - New Eval-PCB, FPGAs, current measurement, annealing (partial)
- **Next irradiation test**
 - Still work and testing to do, new schedule: test $>\sim 1$ mo away
- **(Non-)Contact w/ Actel rep**
 - Samples, delivery, NDA, est. info path, RT, Univ/Lab program, ...

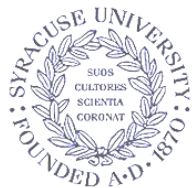
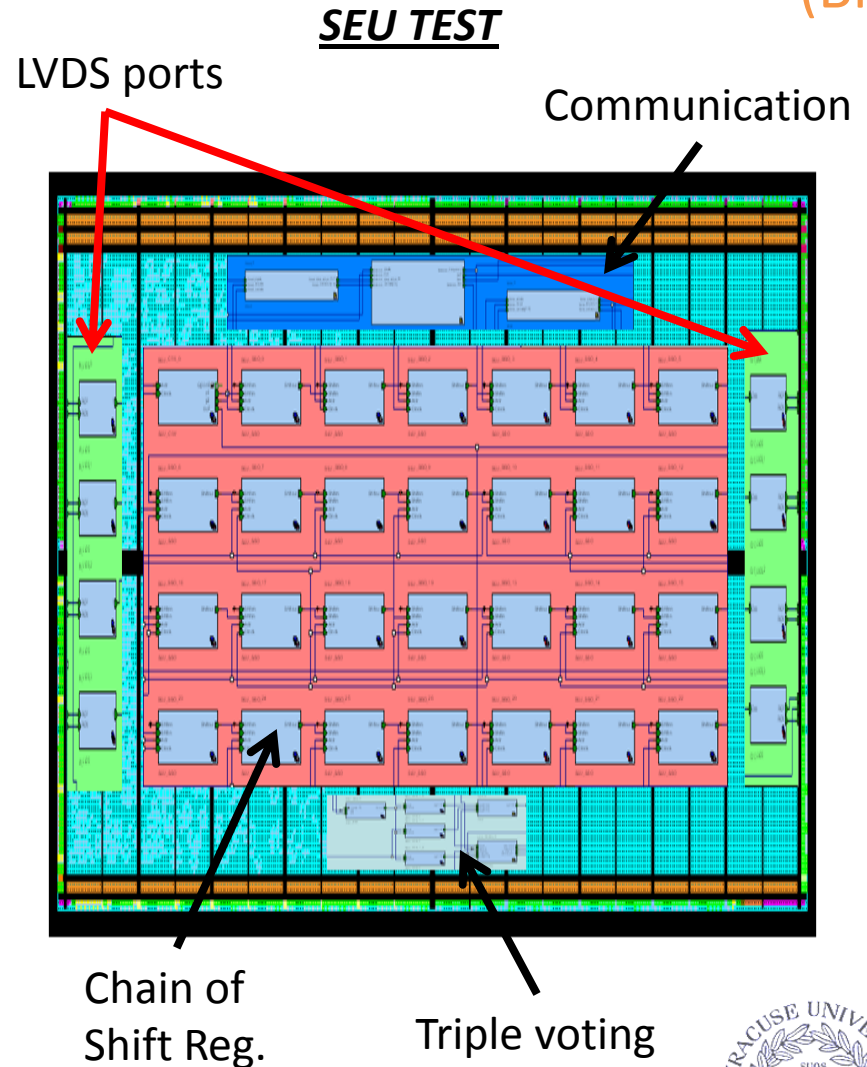
THIS IS STILL WORK IN PROGRESS !



Progress with firmware

- **Had major problems with timing and synchronization at MGH**
 - Difficulties with comparator, communications, etc.
 - Traced to delay module not functioning
 - Now considered solved (see next slides)
- **Re-coded SEU test**
 - Streamlined algo and comm
 - Incorporates new delay scheme (works)
 - Modified to run for a fixed amount of time (~3 mins)
 - Different frequencies: 40, 120, 240 MHz tested, now functional (may adjust if 320 works)
 - Added triple voting into the design on error counter (works)
 - Bench tested for several weeks, seems stable ... see no SEUs (!)
 - Communications still needs to be tested
- **RAM/ROM Memory tests**
 - Take SEU test as baseline
 - Coding in progress
- **Physical constraints for loading code can now be implemented**
 - Select region of logic tile space for program, or for specific module of code
 - Can constrain for irradiation, and also for timing purposes

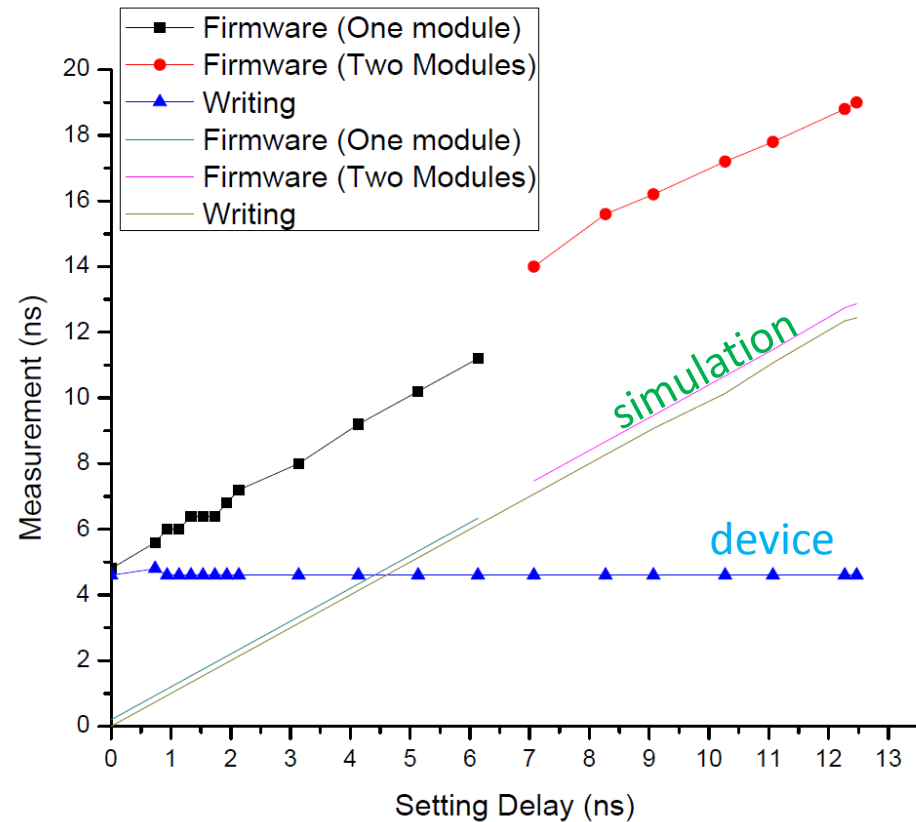
(Bin)



Timing Issues (1)

from
last meeting

- **Some systematic studies of timing**
 - Use a small project, with counter, “firmware” delay (i.e., Actel module), and “writing” delay (VHDL code)
 - Set delay in code, measure delay on scope, get plot shown
- **Timing changes when recompile but not reconfigure**
 - Known (offsets in this plot)
- **Timing delays using Actel module works, timing delays using VHDL block does not work at all**
 - Simulates correctly, of course!
 - Syntactically-correct VHDL
 - Actel compiler didn't flag this as an “error” for this FPGA
 - Really problematic, since Actel module is limited to ~7 ns delay
- **Still have not fully sorted all timing issues**



*still not explained,
but now we have a
workaround*



Timing Issues (2)

(Bin)

	Works?	Time Delay	Measured Value	Time Increment	Linear?	Offset	Physical Size	Usage
Firmware delay (standard Actel block)	YES	0–6.735 ns	set-value + ext.offset [1]	~0.2 ns	YES	<~5 ns / module [1]	global buffer: max. 18	limited to very fine delays
Write delay (VHDL code)	NO	any value	~2ns (i.e., not functional)	—	NO	constant (~2ns)	0	DON'T!
Shift Register delay (FIFO)	YES	N*25 ns (N=2–512 per module) [2]	set-value + ext.offset [1]	25ns / bit [2]	YES	small	depends on length (e.g. 0.12% core for N=20)	large delays (max 12.8 us each SR)
Trigger delay (N-bit Counter, use MSB)	YES	2 ^N *25 ns [2]	set-value + ext.offset [1]	variable, log ₂	YES	small	0.46% core (approx. constant)	control or enable lines

N = number of bits in register

*checked these methods,
take no chances*

Notes:

[1] External offset is a random offset, due to intrinsic physical propagation delays between logic tiles. Can be controlled by fixing location of module in FPGA. Typically <~5 ns/module.

[2] Clock speed 25 ns (for 40 MHz operation).



Progress with hardware

- **Devices**
 - Eval-PCBs: have 3 in hand now
 - FPGAs: have 2 working (+ 1 rad damaged)
- **Setup now for irradiation of two Eval-PCBs at once**
 - Work in progress
 - Most hardware in place, need new transition board, another channel in ac power relay, and few other items for second setup
 - Will take a few more weeks to finish, then test
- **Current monitoring**
 - Current measurement on high side of REG in place
 - Remote monitoring being implemented
- **Annealing tests**
 - Partially done (see next slide)



Annealing

- **Previously...**
 - After 90–127 kRad(Si) dose, latch-up (apparently) caused large current draw in FPGA
 - Reduced Vcc (1.5 V DC core power level), as delivered to chip, and it dropped below lower limit (1.425 V)
 - FPGA stopped functioning. We saw:
 - firmware failure (no comm),
 - configuration failure (EXIT -24, unstable vpump voltage levels),
 - verification failure,
 - no recovery in situ (via power cycle)
 - Estimated Icc \approx 1 A draw (or more)
 - Similar to other hard errors:
 - RT54SX (antifuse device) – current sinking with dose, Icc spikes >80 kRad
 - Other A3P devices – adverse effects (propagation delay, frequency degradation) at doses >70 kRad
- **Follow prescription from Frédéric and Jorgen: 100°C for a week**
- **So far...**
 - **Measure current at 9V DC input to Eval-PCB (pass thru)**
 - High side of REG
 - Expect 0.2 A
 - Measure 2.0 A (max for LDO REG!)
 - **FPGA heats up very fast – few sec to BBQ temps**
 - **Method: Cook @ 100° C, check every 24 hr**
 - Start: 2.0 A
 - After ~24 hr: 2.0 A
 - After ~48 hr: 0.35 A
 - After ~72 hr: 0.35 A
 - **However, cannot program the FPGA**
 - Get same error as previously seen (EXIT-24 fail)
 - **So, continue cooking...**



Next Irradiation Test

- **Our plan was to settle the issues we found and if successful do another round of irradiation (planned for the current time period)**
- **We have settled the timing issue and most of the associated coding issues on SEU test**
- **Still have some work to do to on memory tests, and some of the hardware**
- **Negotiating with MGH for beam schedule; may join with another user**
- **Currently we have resources for one more irradiation test**
- **Revised plan:**
 - Irradiation in May(-ish) time period
 - Two Eval-PCBs at once
 - 3-5 FPGAs to be irradiated



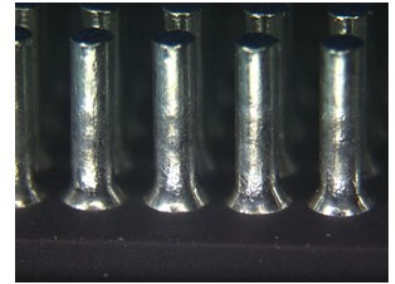
Actel Rep, etc.

- **“Our” Actel rep**
 - Initial meeting 10/15, then effectively disappeared for ~3 mos, due to merger with Microsemi (which seemed chaotic, not a good sign, but hopefully one time thing)
 - Some technical info exchange, but other contact attempts were redirected
 - Resurfaced recently, re-tasked to us, meeting 3/18
 - Next meeting tentatively scheduled for week of 4/11, with “real” engineer and rad tolerant “expert”
- **Several broader issues**
 - NDA: in process since 12/15, yet to establish efficient info path
 - Samples: requested 5, but they appear to be very stingy (we may get 2)
 - Distributors: limited to Future, Mouser, Avnet Memec (Microsemi), Actel Direct (US)
 - Delivery schedules: always appears to be long (8-10 wk)
 - Have “Actel Direct” website for ordering small quantity orders. North America only , probably some European equivalent also? Take advantage of WIP that can be diverted, so can improve lead time. Claim is: can reduce to 4 wk.
 - University/Laboratory program:
 - Actel/Microsemi does not have a University program of any kind in place and it is clear that they really do not know how to handle University or Laboratory groups.
 - Advantageous to try to establish this kind of relationship with them.
 - It would go a long way in dealing with them to represent to them that if we would decide on Actel devices, we will make a centralized buy. That would give them some incentive to be more timely in their response and also provide us with better support and samples.
 - This is something to consider and decide in the long term.
 - For the moment, the line I am taking is that we will order 10 K devices from them in bulk so we’ll see what kind of response that generates, and if we can establish a program with them.

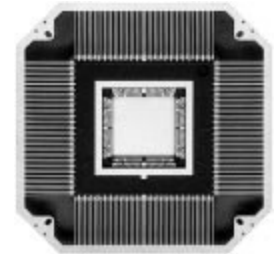


Actel RT ProASIC3

- **Rad-tolerant version of ProASIC3**
 - Many irradiation measurements already made by Actel
 - Recently space qualified (MIL-STD-883 Class B)
- **RT3PE600L and RT3PE3000L are based on ProASIC3-L**
 - Low power
 - ProASIC3-L max oper freq: up to 781.25 MHz
- **Cost**
 - Probably in 1K\$ range
 - Compare \$150 for A3PE1500, ~\$70 for A3P1000L
- **Package**
 - CCGA/CLGA or CQFP only (not PQ208 now)
- **Actel rep: does not think rad data for A3P is going to be requested by Actel (due to RT devices)**
 - So the lever arm for information share back may be minimal
- **Might be useful to investigate RT further...**



**Ceramic Column Grid Array
(Pb/Sn Columns, + Cu)**



Ceramic Quad Flat Pack

